

# 74HCU04A Hex Unbuffered Inverter

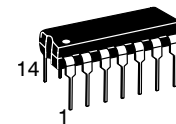
## High-Performance Silicon-Gate CMOS

The 74HCU04A is identical in pinout to the LS04 and the MC14069UB. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LSTTL outputs.

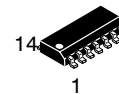
This device consists of six single-stage inverters. These inverters are well suited for use as oscillators, pulse shapers, and in many other applications requiring a high-input impedance amplifier. For digital applications, the HC04A is recommended.

### Features

- Output Drive Capability: 10 LSTTL Loads
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V; 2.5 to 6.0 V in Oscillator Configurations
- Low Input Current: 1  $\mu$ A
- High Noise Immunity Characteristic of CMOS Devices
- In Compliance With the JEDEC Standard No. 7.0 A Requirements
- Chip Complexity: 12 FETs or 3 Equivalent Gates
- Pb-Free Packages are Available

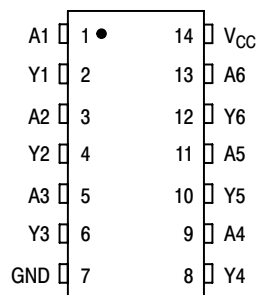


DIP -14  
N SUFFIX  
CASE 646



SOP -14  
D SUFFIX  
CASE 751A

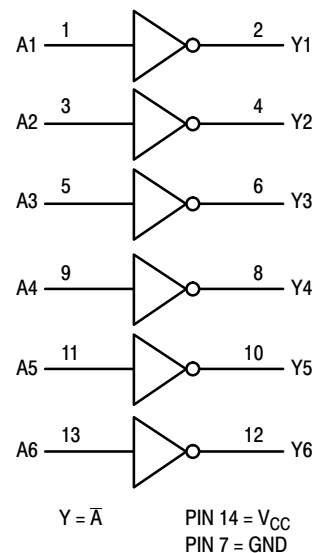
### PIN ASSIGNMENT



### FUNCTION TABLE

Inputs A	Outputs Y
L	H
H	L

### LOGIC DIAGRAM



**MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	- 0.5 to + 7.0	V
V <sub>in</sub>	DC Input Voltage (Referenced to GND)	- 0.5 to V <sub>CC</sub> + 0.5	V
V <sub>out</sub>	DC Output Voltage (Referenced to GND)	- 0.5 to V <sub>CC</sub> + 0.5	V
I <sub>in</sub>	DC Input Current, per Pin	±20	mA
I <sub>out</sub>	DC Output Current, per Pin	±25	mA
I <sub>CC</sub>	DC Supply Current, V <sub>CC</sub> and GND Pins	±50	mA
P <sub>D</sub>	Power Dissipation in Still Air Plastic DIP† SOIC Package† TSSOP Package†	750	mW
		500	
		450	
T <sub>stg</sub>	Storage Temperature	- 65 to + 150	°C
T <sub>L</sub>	Lead Temperature, 1 mm from case for 10 Seconds Plastic DIP, SOIC or TSSOP Package	260	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V<sub>in</sub> and V<sub>out</sub> should be constrained to the range GND ≤ (V<sub>in</sub> or V<sub>out</sub>) ≤ V<sub>CC</sub>. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V<sub>CC</sub>). Unused outputs must be left open.

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

† Derating — Plastic DIP: -10mW/°C from 65° to 125°C  
 SOIC Package: -7mW/°C from 65° to 125°C  
 TSSOP Package: - 6.1 mW/°C from 65° to 125°C

For high frequency or heavy load considerations, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

**RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	2.0	6.0	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Referenced to GND)	0	V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature, All Package Types	- 55	+ 125	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time (Figure 1)	-	No Limit	ns

**DC ELECTRICAL CHARACTERISTICS** (Voltages Referenced to GND)

Symbol	Parameter	Test Conditions	V <sub>CC</sub> V	Guaranteed Limit			Unit
				- 55 to 25°C	≤ 85°C	≤ 125°C	
V <sub>IH</sub>	Minimum High-Level Input Voltage	V <sub>out</sub> = 0.5 V*  I <sub>out</sub>   ≤ 20 μA	2.0	1.7	1.7	1.7	V
			3.0	2.5	2.5	2.5	
			4.5	3.6	3.6	3.6	
			6.0	4.8	4.8	4.8	
V <sub>IL</sub>	Maximum Low-Level Input Voltage	V <sub>out</sub> = V <sub>CC</sub> - 0.5 V*  I <sub>out</sub>   ≤ 20 μA	2.0	0.3	0.3	0.3	V
			3.0	0.5	0.5	0.5	
			4.5	0.8	0.8	0.8	
			6.0	1.1	1.1	1.1	
V <sub>OH</sub>	Minimum High-Level Output Voltage	V <sub>in</sub> = GND  I <sub>out</sub>   ≤ 20 μA	2.0	1.8	1.8	1.8	V
			4.5	4.0	4.0	4.0	
			6.0	5.5	5.5	5.5	
		V <sub>in</sub> = GND  I <sub>out</sub>   ≤ 2.4 mA  I <sub>out</sub>   ≤ 4.0 mA  I <sub>out</sub>   ≤ 5.2 mA	3.0	2.36	2.26	2.20	
			4.5	3.86	3.76	3.70	
			6.0	5.36	5.26	5.20	

**DC ELECTRICAL CHARACTERISTICS** (Voltages Referenced to GND)

Symbol	Parameter	Test Conditions	V <sub>CC</sub> V	Guaranteed Limit			Unit
				- 55 to 25°C	≤ 85°C	≤ 125°C	
V <sub>OL</sub>	Maximum Low-Level Output Voltage	V <sub>in</sub> = V <sub>CC</sub>  I <sub>out</sub>   ≤ 20 μA	2.0	0.2	0.2	0.2	V
			4.5	0.5	0.5	0.5	
			6.0	0.5	0.5	0.5	
		V <sub>in</sub> = V <sub>CC</sub>  I <sub>out</sub>   ≤ 2.4 mA  I <sub>out</sub>   ≤ 4.0 mA  I <sub>out</sub>   ≤ 5.2 mA	3.0	0.32	0.32	0.32	
			4.5	0.32	0.37	0.40	
			6.0	0.32	0.37	0.40	
I <sub>in</sub>	Maximum Input Leakage Current	V <sub>in</sub> = V <sub>CC</sub> or GND	6.0	±0.1	±1.0	±1.0	μA
I <sub>CC</sub>	Maximum Quiescent Supply Current (per Package)	V <sub>in</sub> = V <sub>CC</sub> or GND I <sub>out</sub> = 0 μA	6.0	1	10	40	μA

- Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).
- For V<sub>CC</sub> = 2.0 V, V<sub>out</sub> = 0.2 V or V<sub>CC</sub> - 0.2 V.

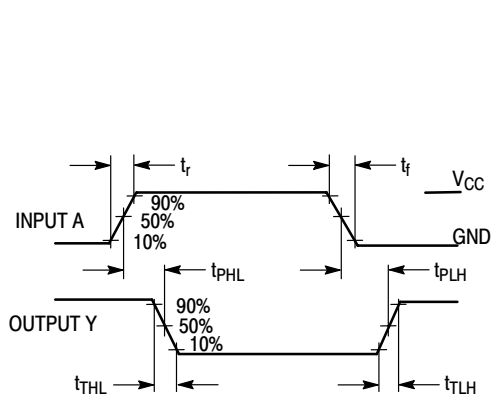
**AC ELECTRICAL CHARACTERISTICS** (C<sub>L</sub> = 50 pF, Input t<sub>r</sub> = t<sub>f</sub> = 6 ns)

Symbol	Parameter	V <sub>CC</sub> V	Guaranteed Limit			Unit
			- 55 to 25°C	≤ 85°C	≤ 125°C	
t <sub>PLH</sub> , t <sub>PHL</sub>	Maximum Propagation Delay, Input A to Output Y (Figures 1 and 2)	2.0	70	90	105	ns
		3.0	40	45	50	
		4.5	14	18	21	
		6.0	12	15	18	
t <sub>TLH</sub> , t <sub>THL</sub>	Maximum Output Transition Time, Any Output (Figures 1 and 2)	2.0	75	95	110	ns
		3.0	27	32	36	
		4.5	15	19	22	
		6.0	13	16	19	
C <sub>in</sub>	Maximum Input Capacitance	—	10	10	10	pF

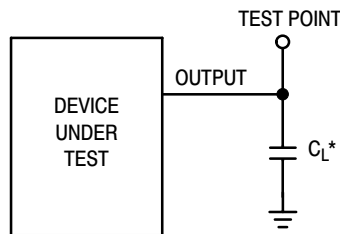
- For propagation delays with loads other than 50 pF, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).
- Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

C <sub>PD</sub>	Power Dissipation Capacitance (Per Inverter)*	Typical @ 25°C, V <sub>CC</sub> = 5.0 V		pF
		15		

- Used to determine the no-load dynamic power consumption: P<sub>D</sub> = C<sub>PD</sub> V<sub>CC</sub><sup>2</sup>f + I<sub>CC</sub> V<sub>CC</sub>. For load considerations, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

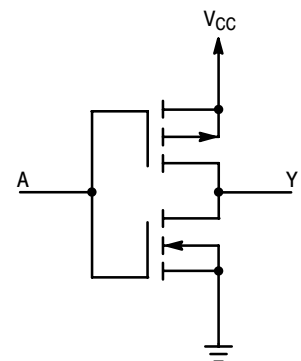


**Figure 1. Switching Waveforms**



\*Includes all probe and jig capacitance

**Figure 2. Test Circuit**



**Figure 3. Logic Detail**  
(1/6 of Device Shown)

TYPICAL APPLICATIONS

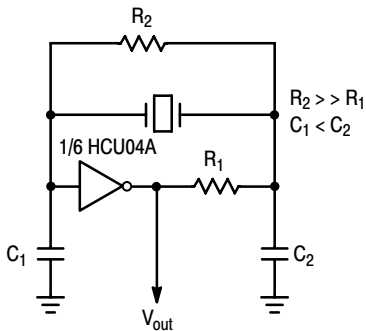


Figure 4. Crystal Oscillator

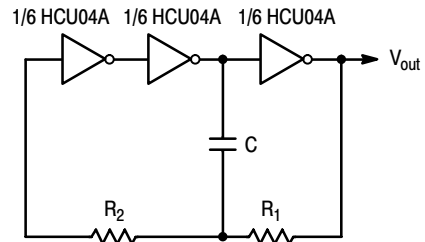


Figure 5. Stable RC Oscillator

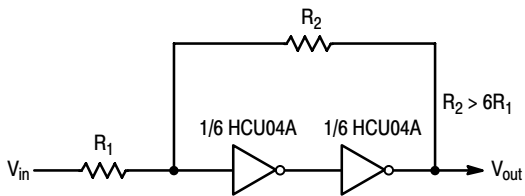


Figure 6. Schmitt Trigger

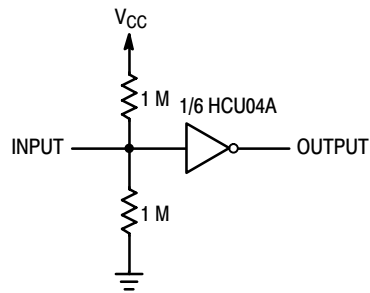


Figure 7. High Input Impedance Single-Stage Amplifier with a 2 to 6 V Supply Range

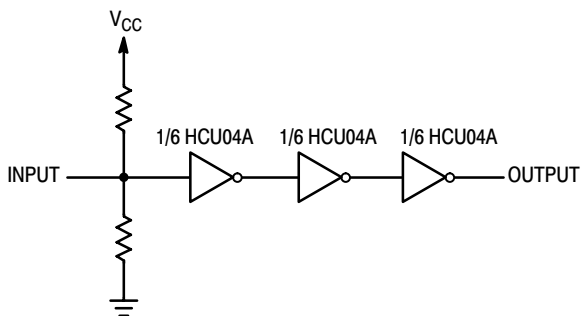
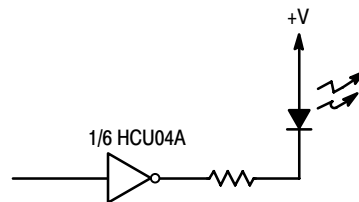


Figure 8. Multi-Stage Amplifier



For reduced power supply current, use high-efficiency LEDs such as the Hewlett-Packard HLMP series or equivalent.

Figure 9. LED Driver